

ON Semiconductor®

FDS8958A-F085

Dual N & P-Channel PowerTrench® MOSFET

General Description

These dual N- and P-Channel enhancement mode power field effect transistors are produced using ON Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state ressitance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

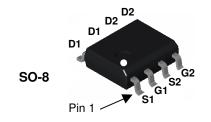
Q1: N-Channel

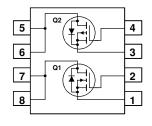
7.0A, 30V
$$R_{DS(on)} = 0.028\Omega$$
 @ $V_{GS} = 10V$ $R_{DS(on)} = 0.040\Omega$ @ $V_{GS} = 4.5V$

• Q2: P-Channel

$$_{DS(on)} = 0.052\Omega$$
 @ $_{QS} = -10V$ $_{DS(on)} = 0.080\Omega$ @ $_{QS} = -4.5V$

- Fast switching speed
- High power and handling capability in a widely used surface mount package
- Qualified to AEC Q101
- RoHS Compliant





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V _{DSS}	Drain-Source Voltage		30	30	V
V _{GSS}	Gate-Source Voltage		±20	±20	V
I _D	Drain Current - Continuous	(Note 1a)	7	-5	
	- Pulsed		20	-20	Α
P _D	Power Dissipation for Dual Operation		2	2	
	Power Dissipation for Single Operation	(Note 1a)	1.6	1.6	W
		(Note 1c)	0.9	0.9	1
E _{AS}	Single Pulse Avalanche Energy	(Note 3)	54	13	mJ
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to	°C	

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS8958A	FDS8958A-F085	13"	12mm	2500 units

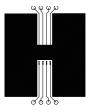
Symbol	Parameter	Test	Conditions	Type	Min	Тур	Max	Units
Off Cha	racteristics							
BV _{DSS}	Drain-Source Breakdown Voltage		I _D = 250 μA I _D = -250 μA	Q1 Q2	30 -30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu A, F$	Referenced to 25°C Referenced to 25°C	Q1 Q2		25 -23		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V},$	$V_{GS} = 0 V$	Q1 Q2			1 -1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{DS} = -24 \text{ V},$ $V_{GS} = 20 \text{ V},$	$V_{DS} = 0 V$	All			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V},$	$V_{DS} = 0 V$	All			-100	nA
On Cha	racteristics (Note 2)							
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS} = V_{GS},$ $V_{DS} = V_{GS},$	I _D = 250 μA I _D = -250 μA	Q1 Q2	1 -1	1.9 -1.7	3 -3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu A, \ R$	eferenced to 25°C eferenced to 25°C	Q1 Q2		-4.5 4.5		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V},$	I _D = 7 A = 7 A, T _J = 125°C	Q1 Q2		19 27 24 42	28 42 40 52	mΩ
			$= -5 \text{ A}, T_J = 125^{\circ}\text{C}$	Q2		57 65	78 80	
$I_{D(on)}$	On-State Drain Current	$V_{GS} = -10 \text{ V},$	$V_{DS} = -5 V$	Q1 Q2	20 -20			Α
g FS	Forward Transconductance	$V_{DS} = 5 V$, $V_{DS} = -5 V$,	$I_D = 7 A$	Q1 Q2		25 10		S
Dynami	c Characteristics							
C _{iss}	Input Capacitance	Q1 V _{DS} = 15 V, V _{GS}	s = 0 V, f = 1.0 MHz	Q1 Q2		575 528		pF
C _{oss}	Output Capacitance	Q2		Q1 Q2		145 132		pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = -15 \text{ V}, \text{ V}$	_{GS} = 0 V, f = 1.0 MHz	Q1 Q2		65 70		pF
R_{G}	Gate Resistance	$V_{GS} = 15 \text{ mV},$	f = 1.0 MHz	Q1 Q2		2.1 6.0		Ω

Electri	cal Characteristics	(continued) T _A = 25 °C unless othe	rwise noted	I			
Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Switchii	ng Characteristics (Note	2)					
$t_{\text{d(on)}} \\$	Turn-On Delay Time	Q1 V _{DD} = 15 V, I _D = 1 A,	Q1 Q2		8 7	16 14	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V$, $R_{GEN} = 6 \Omega$	Q1 Q2		5 13	10 24	ns
t _{d(off)}	Turn-Off Delay Time	Q2 V _{DD} = -15 V, I _D = -1 A,	Q1 Q2		23 14	37 25	ns
t _f	Turn-Off Fall Time	$V_{GS} = -10V$, $R_{GEN} = 6 \Omega$	Q1 Q2		3	6 17	ns
Qg	Total Gate Charge	Q1 V _{DS} = 15 V, I _D = 7 A, V _{GS} = 10 V	Q1 Q2		11.4 9.6	16 13	nC
Q _{gs}	Gate-Source Charge	Q2	Q1 Q2		1.7 2.2		nC
Q_{gd}	Gate-Drain Charge	$V_{DS} = -15 \text{ V}, I_{D} = -5 \text{ A}, V_{GS} = -10 \text{ V}$	Q1 Q2		2.1 1.7		nC
Drain-S	Source Diode Character	ristics and Maximum Ratings	s				•
Is	Maximum Continuous Drain-Source Diode Forward Current		Q1 Q2			1.3 -1.3	Α
I _{SM}	Maximum Plused Drain-Source Diode Forward Current (Note 2)		Q1 Q2			20 -20	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = -1.3 \text{ A}$ (Note 2)	Q1 Q2		0.75 -0.88	1.2 -1.2	V
t _{rr}	Diode Reverse Recovery Time	Q1 $I_F = 7 \text{ A}, d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$	Q1 Q2		19 19		nS
Q _{rr}	Diode Reverse Recovery	Q2	Q1		9		nC

Notes:

1. R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.

 $I_F = -5 \text{ A}, d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$



a) 78°/W when mounted on a 0.5 in² pad of 2 oz copper



b) 125 °/W when mounted on a .02 in² pad of 2 oz copper



Q2

c) 135 °/W when mounted on a minimum pad.

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- Scale 1:1 on letter size paper
- 2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

Charge

3. Starting TJ = 25 °C, L = 3mH, I_{AS} = 6A, V_{DD} = 30V, V_{GS} = 10V (Q1).

Starting TJ = 25 °C, L = 3mH, I_{AS} = 3A, V_{DD} = 30V, V_{GS} = 10V (Q2).

Typical Characteristics: Q1 (N-Channel)

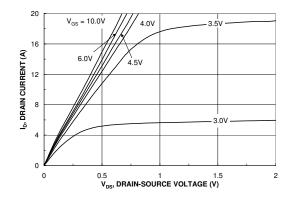
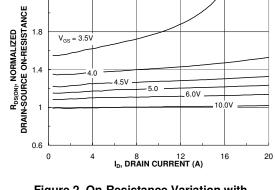


Figure 1. On-Region Characteristics.



2.2

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

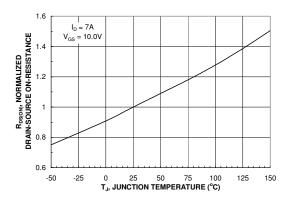


Figure 3. On-Resistance Variation with Temperature.

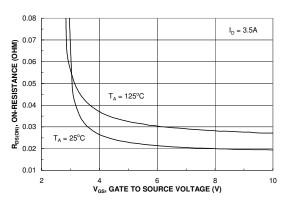


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

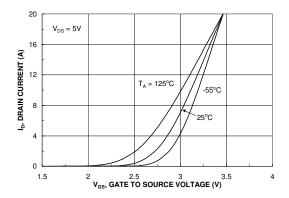


Figure 5. Transfer Characteristics.

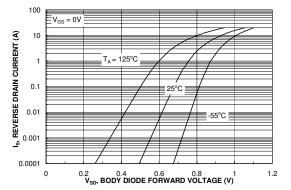
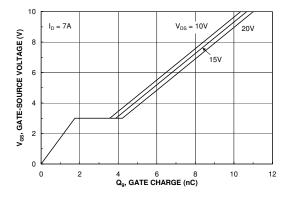


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

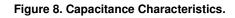
Typical Characteristics: Q1 (N-Channel)

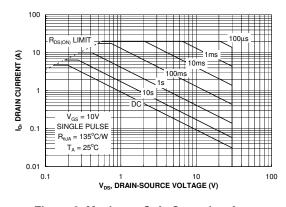


 $C_{iss} = 0 \text{ V}$

800

Figure 7. Gate Charge Characteristics.





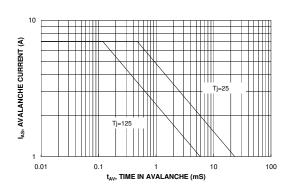


Figure 9. Maximum Safe Operating Area.

Figure 10. Unclamped Inductive Switching Capability Figure

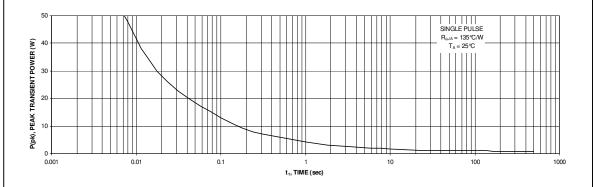


Figure 11. Single Pulse Maximum Power Dissipation.

Typical Characteristics: Q2 (P-Channel)

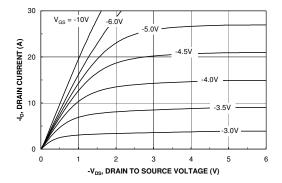


Figure 12. On-Region Characteristics.

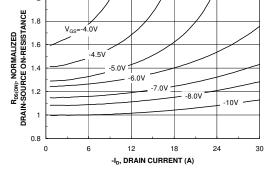


Figure 13. On-Resistance Variation with Drain Current and Gate Voltage.

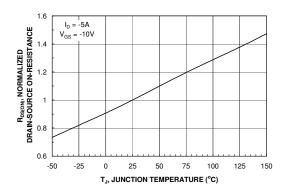


Figure 14. On-Resistance Variation with Temperature.

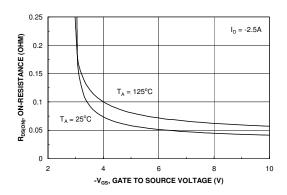


Figure 15. On-Resistance Variation with Gate-to-Source Voltage.

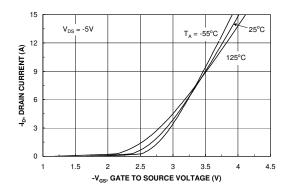


Figure 16. Transfer Characteristics.

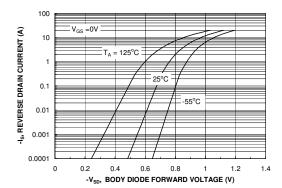


Figure 17. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: Q2 (P-Channel)

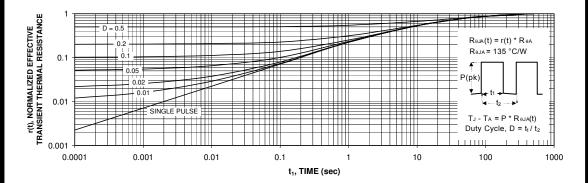


Figure 23. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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